

### General Description

The MDD5N40 use advanced Magnachip's MOSFET Technology, which provides low on-state resistance, high switching performance and excellent quality.

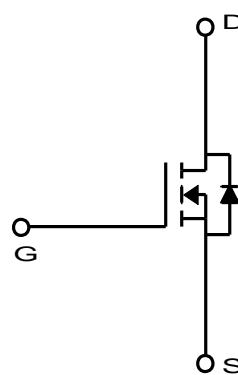
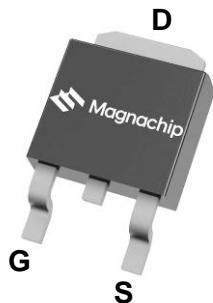
MDD5N40 is suitable device for SMPS, HID and general purpose applications.

### Features

- $V_{DS} = 400V$
- $I_D = 3.4A$  @  $V_{GS} = 10V$
- $R_{DS(ON)} \leq 1.6\Omega$  @  $V_{GS} = 10V$

### Applications

- Power Supply
- PFC
- Ballast



### Absolute Maximum Ratings ( $T_a = 25^\circ C$ )

Characteristics		Symbol	Rating	Unit
Drain-Source Voltage		$V_{DSS}$	400	V
Gate-Source Voltage		$V_{GSS}$	$\pm 30$	V
Continuous Drain Current	$T_C=25^\circ C$	$I_D$	3.4	A
	$T_C=100^\circ C$		2.15	A
Pulsed Drain Current <sup>(1)</sup>		$I_{DM}$	13.6	A
Power Dissipation	$T_C=25^\circ C$	$P_D$	45	W
	Derate above 25 °C		0.36	W/°C
Peak Diode Recovery $dv/dt$ <sup>(3)</sup>		$dv/dt$	4.5	V/ns
Repetitive Pulse Avalanche Energy <sup>(4)</sup>		$E_{AR}$	4.5	mJ
Single Pulse Avalanche Energy <sup>(4)</sup>		$E_{AS}$	170	mJ
Junction and Storage Temperature Range		$T_J, T_{stg}$	-55~150	°C

### Thermal Characteristics

Characteristics		Symbol	Rating	Unit
Thermal Resistance, Junction-to-Ambient <sup>(1)</sup>		$R_{\theta JA}$	110	°C/W
Thermal Resistance, Junction-to-Case <sup>(1)</sup>		$R_{\theta JC}$	2.75	

## Ordering Information

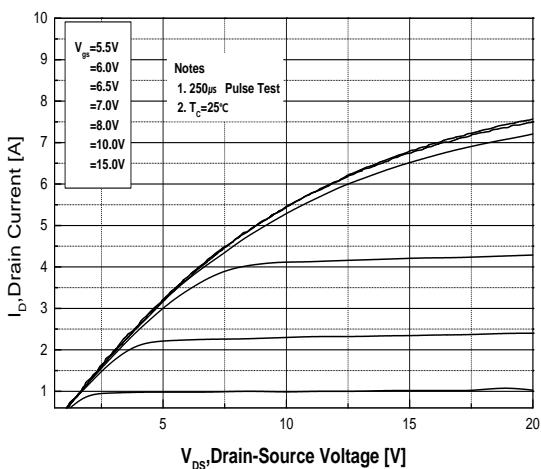
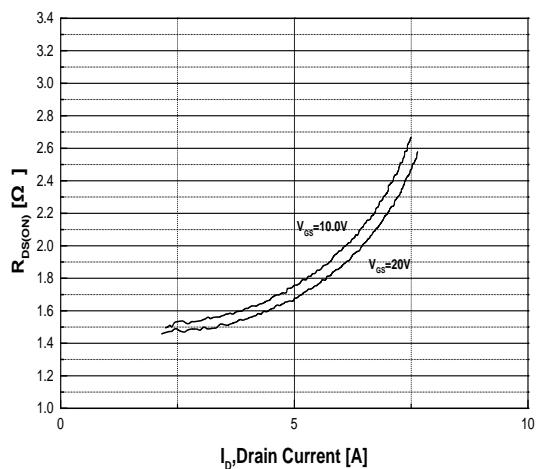
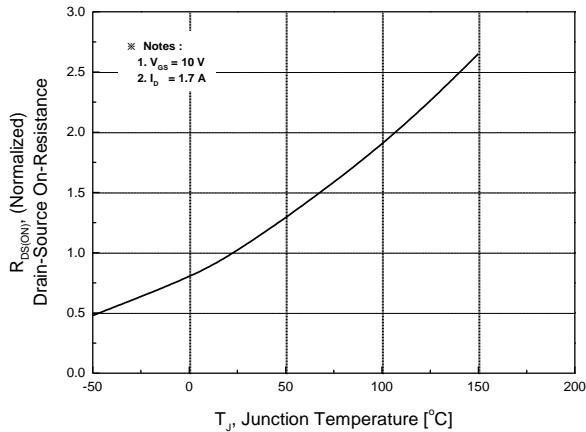
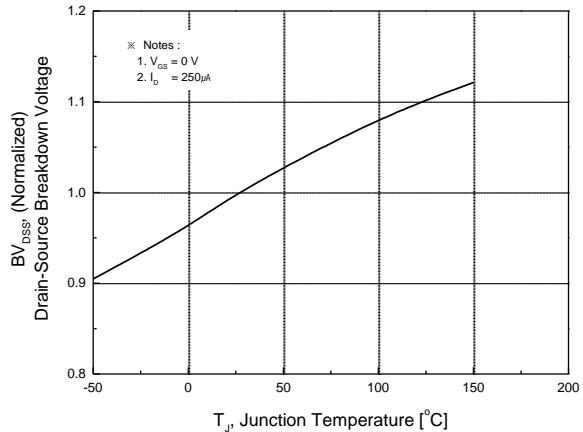
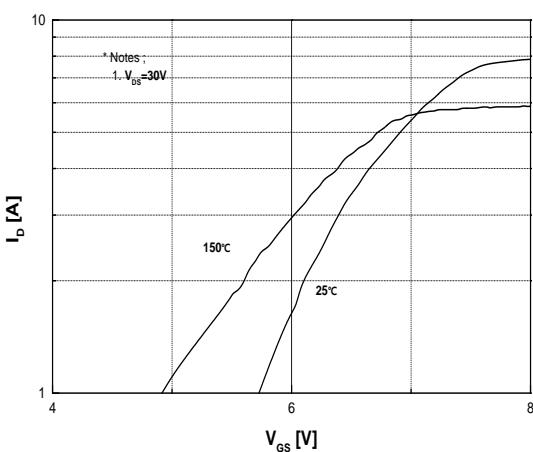
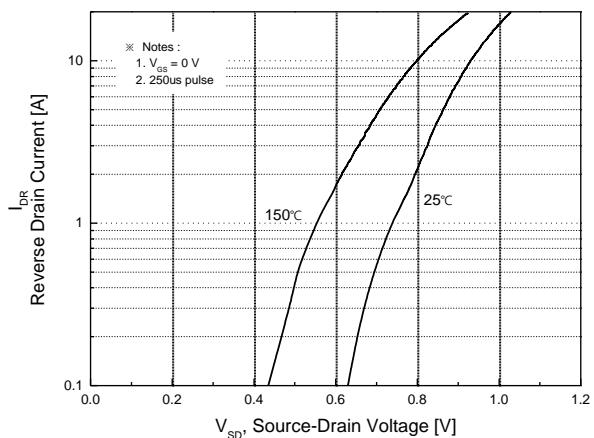
Part Number	Marking	Temp. Range	Package	Packing	RoHS Status
MDD5N40RH	MDD5N40	-55~150°C	TO-252(DPAK)	Reel and Tape	Halogen Free

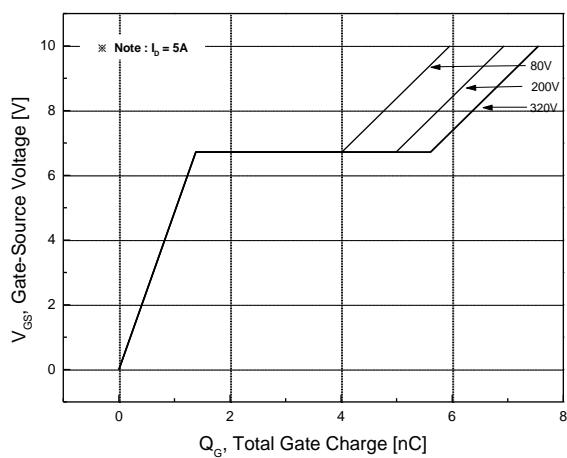
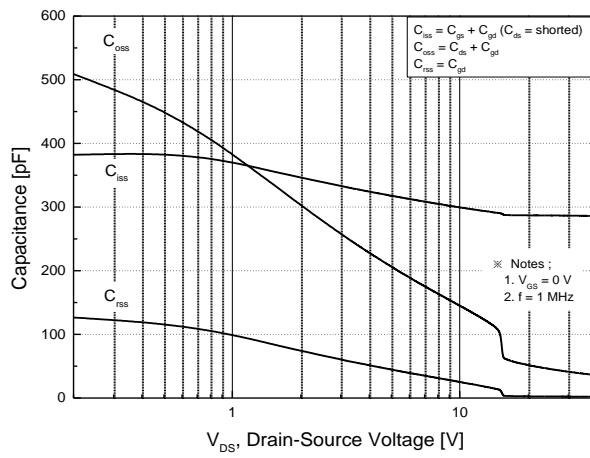
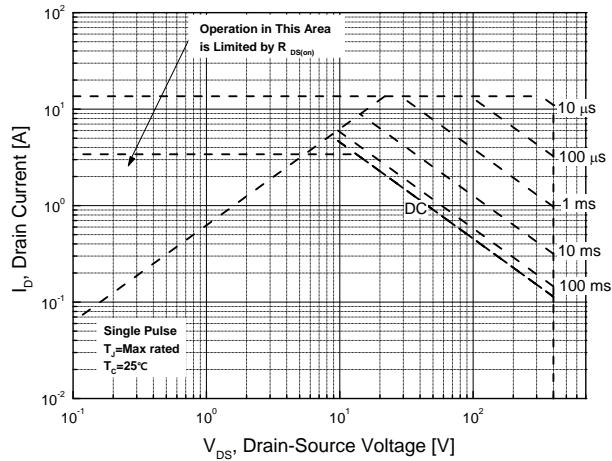
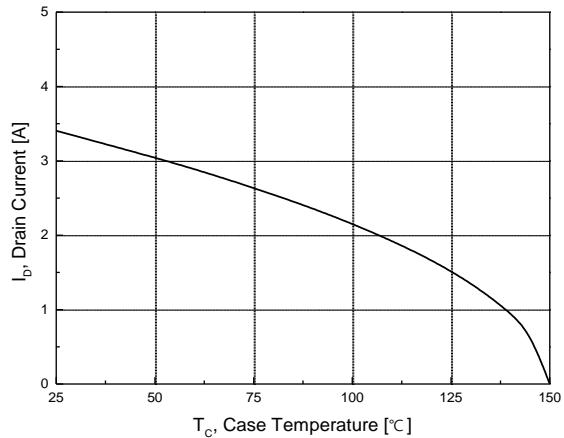
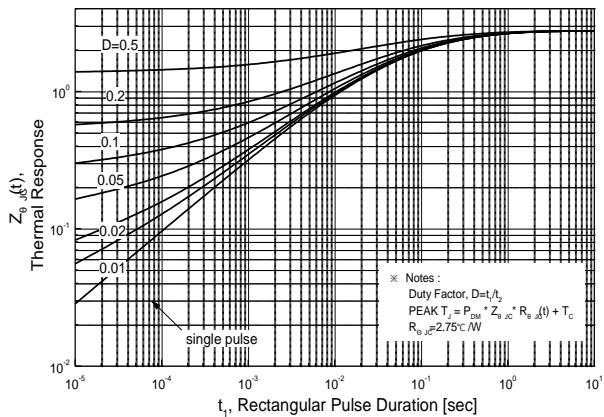
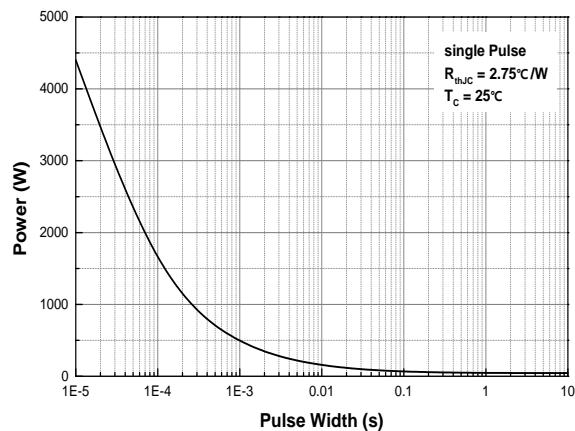
## Electrical Characteristics (Ta =25°C)

Characteristics	Symbol	Test Condition	Min	Typ	Max	Unit
<b>Static Characteristics</b>						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>D</sub> = 250μA, V <sub>GS</sub> = 0V	400	-	-	V
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	3.0	-	5.0	
Drain Cut-Off Current	I <sub>DSS</sub>	V <sub>DS</sub> = 400V, V <sub>GS</sub> = 0V	-	-	1	μA
Gate Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> = ±30V, V <sub>DS</sub> = 0V	-	-	100	nA
Drain-Source ON Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 1.7A		1.2	1.6	Ω
Forward Transconductance	g <sub>fs</sub>	V <sub>DS</sub> = 30V, I <sub>D</sub> = 1.7A	-	2.0	-	S
<b>Dynamic Characteristics</b>						
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = 320V, I <sub>D</sub> = 3.4A, V <sub>GS</sub> = 10V <sup>(3)</sup>	-	9		nC
Gate-Source Charge	Q <sub>gs</sub>		-	2.5		
Gate-Drain Charge	Q <sub>gd</sub>		-	4		
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	-	290		pF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	3		
Output Capacitance	C <sub>oss</sub>		-	46		
Turn-On Delay Time	t <sub>d(on)</sub>	V <sub>GS</sub> = 10V, V <sub>DS</sub> = 200V, I <sub>D</sub> = 3.4A, R <sub>G</sub> = 25Ω <sup>(3)</sup>	-	12		ns
Rise Time	t <sub>r</sub>		-	25		
Turn-Off Delay Time	t <sub>d(off)</sub>		-	20		
Fall Time	t <sub>f</sub>		-	30		
<b>Drain-Source Body Diode Characteristics</b>						
Maximum Continuous Drain to Source Diode Forward Current	I <sub>S</sub>	I <sub>S</sub> = 3.4A, V <sub>GS</sub> = 0V	-	3.4	-	A
Source-Drain Diode Forward Voltage	V <sub>SD</sub>		-		1.4	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>		-	200		ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>		-	1.0		μC

Note :

1. Pulse width is based on R<sub>θJC</sub> & R<sub>θJA</sub> and the maximum allowed junction temperature of 150°C.
2. Pulse test: pulse width≤300us, duty cycle≤2%, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C.
3. I<sub>SD</sub>≤3.4A, di/dt≤200A/us, V<sub>DD</sub>=50V, R<sub>g</sub>=25Ω, Starting T<sub>J</sub>=25°C
4. L=26.0mH, I<sub>AS</sub>=3.4A, V<sub>DD</sub>=50V, R<sub>g</sub>=25Ω, Starting T<sub>J</sub>=25°C

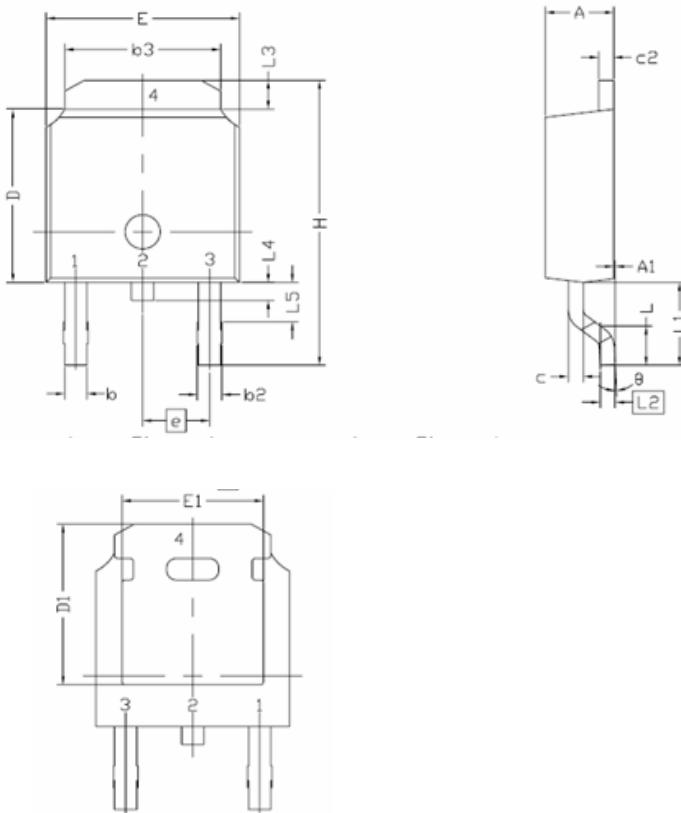

**Fig.1 On-Region Characteristics**

**Fig.2 On-Resistance Variation with Drain Current and Gate Voltage**

**Fig.3 On-Resistance Variation with Temperature**

**Fig.4 Breakdown Voltage Variation vs. Temperature**

**Fig.5 Transfer Characteristics**

**Fig.6 Body Diode Forward Voltage Variation with Source Current and Temperature**


**Fig.7 Gate Charge Characteristics**

**Fig.8 Capacitance Characteristics**

**Fig.9 Maximum Safe Operating Area**

**Fig.10 Maximum Drain Current vs. Case Temperature**

**Fig.11 Transient Thermal Response Curve**

**Fig.12 Single Pulse Maximum Power Dissipation**

## Physical Dimension

### TO-252 (DPAK)

Dimensions are in millimeters, unless otherwise specified



Symbol	Min.	Nom.	Max.
E	6.35	-	6.73
L	1.40	1.52	1.78
L1		2.74 REF	
L2		0.508 BCS	
L3	0.89	-	1.27
L4	-	-	1.02
L5	1.14	-	1.52
D	5.97	6.10	6.22
H	9.40	-	10.41
b	0.64	-	0.89
b2	0.76	-	1.14
b3	4.95	-	5.46
e		2.286 BSC	
A	2.18	-	2.39
A1	-	-	0.13
c	0.46	-	0.61
c2	0.46	-	0.89
D1	5.21	-	-
E1	4.32	-	-
Φ	0.00	-	10.00

**DISCLAIMER:**

The Products are not designed for use in hostile environments, including, without limitation, aircraft, nuclear power generation, medical appliances, and devices or systems in which malfunction of any Product can reasonably be expected to result in a personal injury. Seller's customers using or selling Seller's products for use in such applications do so at their own risk and agree to fully defend and indemnify Seller.

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